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Application/Control No.	Applicant(s)/Patent under Reexamination
10/725,423	OKUTSU ET AL.
Examiner	Art Unit
Yuzhen Ge	2624

	SEARCHED				
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR) - See search history printout	7/10/2007	YG
Search 382/162 with text limitations	7/10/2007	YG